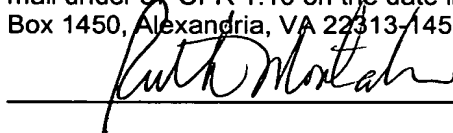


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/ **Ruth Montalvo** Date: **11/19/03**

Customer No. 026418

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket No. **SANKY P-244 / 500615.20210**

Applicant(s): **Hiroshi SAKAI**

Application No.:

Filed: **Concurrently herewith**

For: **LIGHT INTENSITY DISTRIBUTION MEASURING METHOD AND LIGHT INTENSITY DISTRIBUTION MEASURING DEVICE**

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

S I R:

Applicant herewith submits together with the simultaneously patent application this Information Disclosure Statement in accordance with the provisions of 37 C.F.R. §§ 1.97 and 1.98, and hereby make of record the following references:

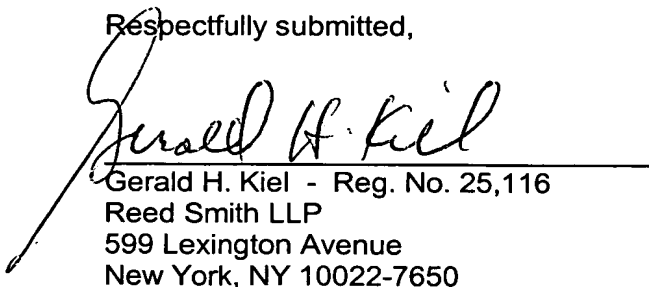
OTHER PRIOR ART (*Including Author, Title, Date, Pertinent Pages, Etc.*)

AV "Nonlinear Least Squares" by Dennis J. E., Jr., State of the Art in numerical Analysis ed. D. Jacobs, Academic Press, pp. 269-312, 1977

Accompanying this Information Disclosure Statement and form PTO-1449, a copy of the article is not readily available. Document AV is mentioned on page 9 of the specification.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,



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599 Lexington Avenue
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11/19/03
GHK:ram

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Enclosures:
PTO-1449

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on November 19, 2003)

Docket No. SANKY P-244 / 500615.20210

Applicant(s): Hiroshi SAKAI

Application No.

Group:

Filed: concurrently herewith –November 19, 2003

Examiner:

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AA						
	AB						
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	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							
	AS							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AV	"Nonlinear Least Squares" by Dennis J. E., Jr., State of the Art in numerical Analysis ed. D. Jacobs, Academic Press, pp. 269-312, 1977
	AW	
	AX	
	AY	
	AZ	

Examiner:

Date:

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.